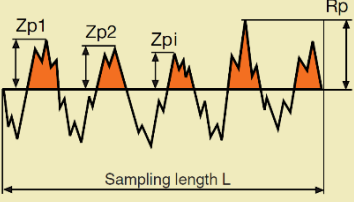
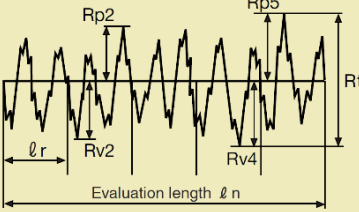
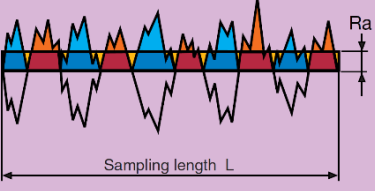
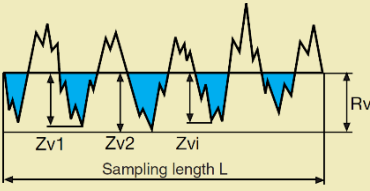
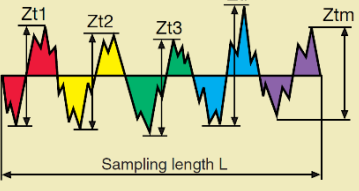
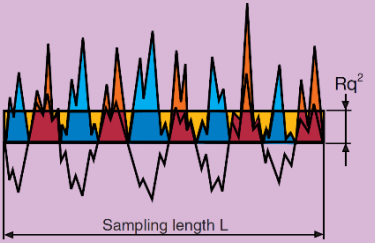
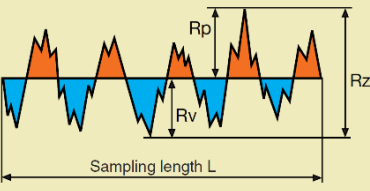
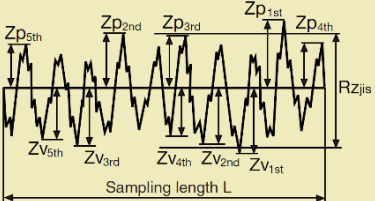
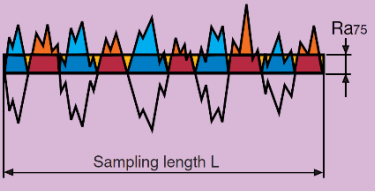


Basic surface texture parameters and curves

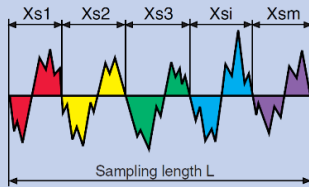
Amplitude parameters (peak and valley)		Amplitude average parameters
Rp Pp Wp } Maximum profile peak height The largest profile peak height Zp within a sampling length. $R_p, P_p, W_p = \max (Z(x))$ 	Rt Pt Wt } Total height of profile (Pt = Rmax at JIS'82) Sum of height of the largest profile peak height Rp and the largest profile valley Rv within an evaluation length. $R_t, P_t, W_t = \max (R_{pi}) + \max (R_{vi})$ 	Ra Pa Wa } Arithmetical mean deviation Arithmetic mean of the absolute ordinate values Z(x) within a sampling length. $R_a, P_a, W_a = \frac{1}{L} \int_0^L Z(x) dx$ 
Rv Pv Wv } Maximum profile valley depth The largest profile valley depth Zp within a sampling length. $R_v, P_v, W_v = \min (Z(x))$ 	Rc Pc Wc } Mean height of profile elements Mean value of the profile element heights Zti within a sampling length. $R_c, P_c, W_c = \frac{1}{m} \sum_{i=1}^m Z_{ti}$  Profile element: Profile peak & the adjacent valley	Rq Pq Wq } Root mean square deviation Root mean square value of the ordinate values Z(x) within a sampling length. $R_q, P_q, W_q = \sqrt{\frac{1}{L} \int_0^L Z^2(x) dx}$ 
Rz Pz Wz } Maximum height of profile (Rz = Ry at ISO4287 '84) Sum of height of the largest profile peak height Rp and the largest profile valley Rv within a sampling length. $R_z = R_p + R_v$  Different from Rz at old ISO, ANSI & JIS	Rzjis Ten point height of roughness profile (Rz at JIS'94) Sum of mean value of largest peak to the fifth largest peak and mean value of largest valley to the fifth largest valley within a sampling length. $R_{zjis} = \frac{1}{5} \sum_{j=1}^5 (Z_{pj} + Z_{vj})$  Annex of JIS only and confirm to JIS'94 Different from Rz at JIS'82	Ra75 Center line average (Old Ra, AA, CLA) Arithmetic mean of the absolute ordinate value Z(x) in a sampling length of roughness profile with 2RC filter of 75% transmission. $R_{a75} = \frac{1}{\ell_n} \int_0^{\ell_n} Z(x) dx$  Annex of JIS only Same as Ra at old ISO, ANSI & DIN

Spacing parameters

RSm
Psm
Wsm } Mean width of the profile elements
(RSm = Sm at ISO4287 '84)

Mean value of the profile element width X_s within a sampling length.

$$RSm, Psm, Wsm = \frac{1}{m} \sum_{i=1}^m X_{si}$$

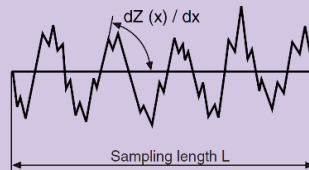


Hybrid parameters

RΔq
PΔq
WΔq } Root mean square slope

Root mean square value of the ordinate slopes dZ/dx within a sampling length.

$$\left. \begin{matrix} R\Delta q \\ P\Delta q \\ W\Delta q \end{matrix} \right\} = \sqrt{\frac{1}{L} \int_0^L \left(\frac{d}{dx} Z(x) \right)^2 dx}$$

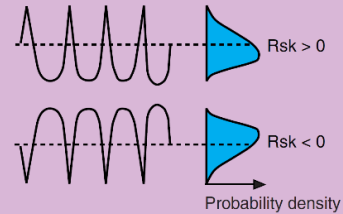


Height characteristic average parameters

Rsk
Psk
Wsk } Skewness

Quotient of mean cube value of the ordinate values $Z(x)$ and cube Pq, Rq, Wq respectively, within a sampling length.

$$Rsk = \frac{1}{Rq^3} \left[\frac{1}{\ell} \int_0^{\ell} Z^3(x) dx \right]$$



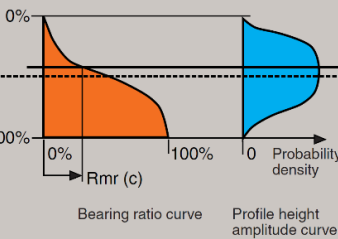
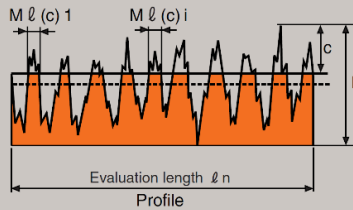
Parameter from bearing ratio curve and profile height amplitude curve

Material ratio curve of the profile
(Abbott Firestone curve)

Curve representing the material ratio of the profile as a functional of level c .

Profile height amplitude curve

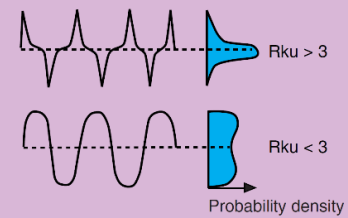
Sample probability density function of ordinate $Z(x)$ within an evaluation length.



Rku
Pku
Wku } Kurtosis of profile

Quotient of mean quartic of the ordinate values $Z(x)$ and 4th power of Pq, Rq, Wq respectively, within a sampling length.

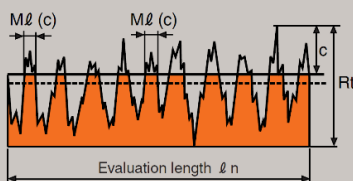
$$Rku = \frac{1}{Rq^4} \left[\frac{1}{\ell} \int_0^{\ell} Z^4(x) dx \right]$$



Rmr(c)
Pmr(c)
Wmr(c) } Material ratio of profile
($Rmr(c) = ex - tp$)

Ratio of the material length of the profile elements $Ml(c)$ at a given level c to the evaluation length.

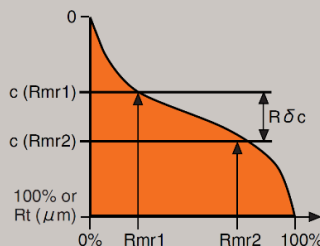
$$Rmr(c) = \frac{100}{\ell n} \sum_{i=1}^m Ml(c)_i (\%)$$



Rδc
Pδc
Wδc } Profile section height difference

Vertical distance between two section levels of given material ratio.

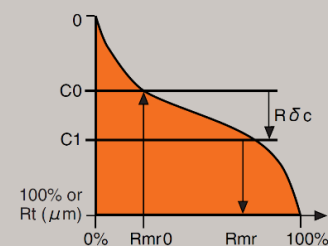
$$R\delta c = c(Rmr1) - c(Rmr2) : Rmr1 < Rmr2$$



Rmr
Pmr
Wmr } Relative material ratio

Material ratio determined at a profile section level $R\delta c$, related to a reference c_0 .

$$Rmr = Rmr(c_1) \\ C_1 = C_0 - R\delta c, C_0 = C(Rmr0)$$



Expanded surface texture parameters and curves

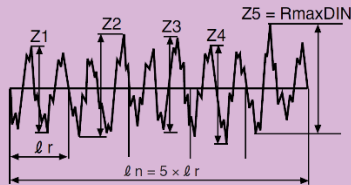
Confirm to ISO4287: '96, ISO12085: '96
& ISO13565-1: '96 / -2: '96 / -3: '98

Traditional local parameters

RmaxDIN Maximum peak to valley height
RzDIN Average peak to valley height

Zi is the maximum Peak to valley height of a sampling length ℓr .
RmaxDIN is the maximum Zi of 5 adjoining sampling length ℓr in an evaluation length ℓn .
RzDIN is arithmetic mean of 5 Zi.

$$RzDIN = \frac{1}{n} \sum_{i=1}^n Zi$$



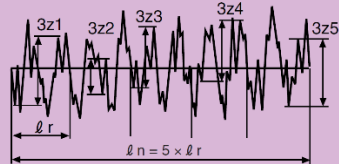
German old standard DIN4768/1: '90

R3z Base roughness depth

3Zi is the height of the 3rd height peak from the 3rd depth valley in a sampling length ℓr .

R3z is arithmetic mean of 3Zi's of 5 sampling lengths in an evaluation length ℓn .

$$R3z = \frac{1}{n} \sum_{i=1}^n 3zi$$

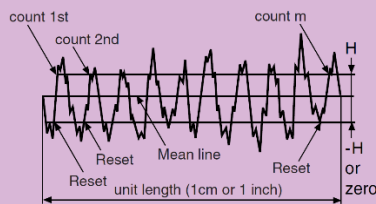


Pc Peak density /cm: ASME B46.1: '95

PPI Peaks per inch: SAEJ911

HSC High spot count

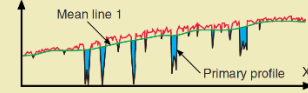
Pc is the number of peaks counted when a profile intersects a lower boundary line -H and an upper line +H per unit length 1 cm.
PPI shows Pc in 1 inch (25.4mm) unit length.
HSC shows the number of peaks when the lower boundary level is equal to zero.



Parameters of surfaces having stratified functional properties ISO13565's

Filtering process of ISO13565-1: '96

Calculate mean line 1 from a primary profile with phase correct filter.



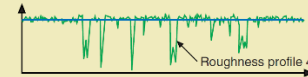
Calculate profile 2 with cutting valley lower than mean line 1.



Calculate mean line 3 from profile 2 with phase correct filter.



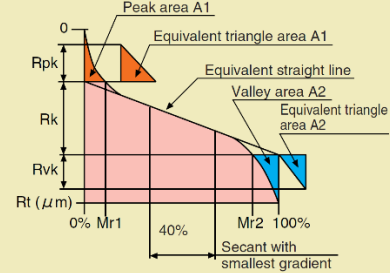
Calculate roughness profile 4 by taking mean line 3 off from a primary profile.



Measuring conditions of ISO13565-1

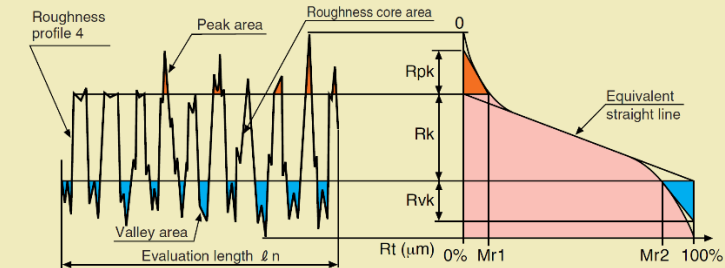
Cutoff value λc	Evaluation length ℓn
0.8 mm	4 mm
2.5 mm	12.5 mm

40% length secant of smallest gradient separate the material ratio curve into core area & projected areas.
Calculate Rpk & Rvk with equivalent triangles of projected areas.



Height characterization using the linear material ratio curve ISO13565-2: '96

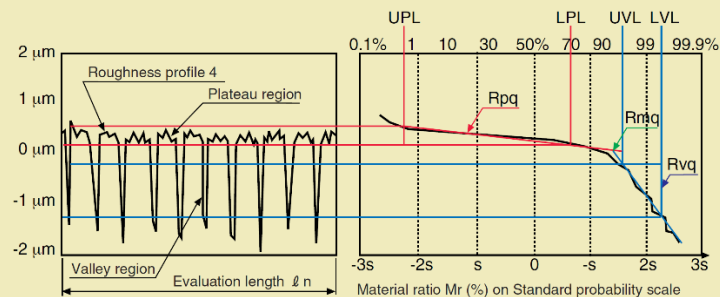
- Rk** core roughness depth : Depth of the roughness core profile
- Rpk** reduced peak height : Average height of protruding peaks above roughness core profile.
- Rvk** reduced valley depths : Average depth of valleys projecting through roughness core profile.
- Mr1** material portion 1 : Level in %, determined for the intersection line which separates the protruding peaks from the roughness core profile.
- Mr2** material portion 2 : Level in %, determined for the intersection line which separates the deep valleys from the roughness core profile.



Height characterization using the material probability curve of ISO13565-3

Draw a material ratio curve on normal probability paper from the roughness profile 4 (primary profile) of an evaluation length.
Separate the material probability curve to 2 area, upper plateau area and lower valley area.

- Rpq (Ppq)** parameter: slope of a linear regression performed through the plateau region.
- Rvq (Pvq)** parameter: slope of a linear regression performed through the valley region.
- Rmq (Pmq)** parameter: relative material ratio at the plateau to valley intersection.



Motif parameters of ISO12085: '96

Motif

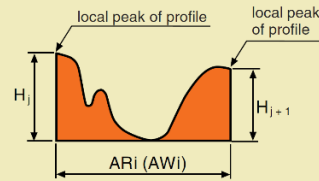
A portion of the primary profile between the highest points of two local peaks of the profile, which are not necessarily adjacent.

Motif depths H_j & H_{j+1}

Depth measured perpendicular to the general direction of the primary profile.

Motif length A_{ri} or A_{wi}

Length measured parallel to the general direction of the profile.



Measuring condition

Default A=0.5mm, B=2.5mm, $\ell n=16$ mm			
A (mm)	B (mm)	ℓn (mm)	λ_s (μm)
0.02	0.1	0.64	2.5
0.1	0.5	3.2	2.5
0.5	2.5	16	8
2.5	12.5	80	25

Indication of ISO1302: '02

Roughness motif

$$\sqrt{\lambda_s - A} / \ell n / R \text{ parameter} \quad \text{limit value}$$

Waviness motif

$$\sqrt{A - B} / \ell n / W \text{ parameter} \quad \text{limit value}$$

(default value need not to be indicated)

Roughness motif: Motif derived by using the ideal operator with limit value A.

Limit value A: Maximum length of roughness motif to separate waviness motif.

Upper envelope line of the primary profile (Waviness profile): Straight lines joining the highest points of peaks of the primary profile, after conventional discrimination of peaks.

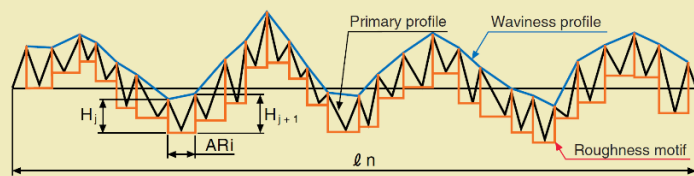
AR: Mean spacing of roughness motifs: The arithmetical mean value of the lengths A_{ri} of roughness motifs, within the evaluation length, i.e.

$$AR = \frac{1}{n} \sum_{i=1}^n A_{ri} \quad (n: \text{Total number of roughness motifs})$$

R: Mean depth of roughness motifs: The arithmetical mean value of the depths H_j of roughness motifs, within the evaluation length, i.e.

$$R = \frac{1}{m} \sum_{j=1}^m H_j \quad m = 2n$$

Rx: Maximum depth of roughness motifs: The maximum value of the depths H_j of roughness motifs, within the evaluation length.



Waviness motif: Motif derived on upper envelope line by using ideal operator with limit value B

Limit value B: Maximum length of waviness motif

AW: Mean spacing of waviness motifs: The arithmetical mean value of the lengths A_{wi} of waviness motifs, within the evaluation length, i.e.

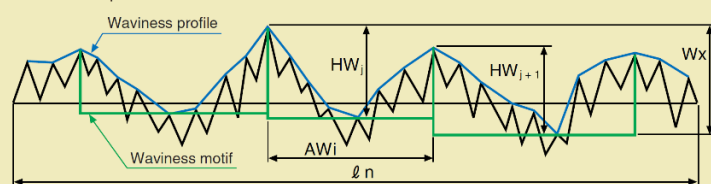
$$AW = \frac{1}{n} \sum_{i=1}^n A_{wi} \quad (n: \text{Total number of waviness motifs})$$

W: mean depth of waviness motifs: The arithmetical mean value of the depths HW_j of waviness motifs, within the evaluation length, i.e.

$$W = \frac{1}{m} \sum_{j=1}^m HW_j \quad m = 2n$$

Wx: Maximum depth of waviness: The largest depth HW_j , within the evaluation length.

Wte: Total depth of waviness: Distance between the highest point and the lowest point of waviness profile.



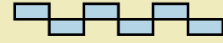
Hint of surface texture measurement

Roughness parameter conversion

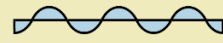
The parameter ratio Ra/Rz (R_{max}, R_y)=0.25 is applicable only to triangle profile.

Actual profiles have different parameter ratios according to the form of profile.

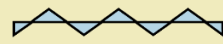
Rectangle: $Ra/Rz=0.5$



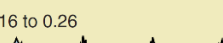
Sinusoidal: $Ra/Rz=0.32$



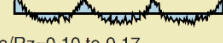
Triangle: $Ra/Rz=0.25$



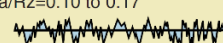
Lathed, Milled: $Ra/Rz=0.16$ to 0.26



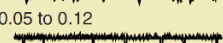
Ground, Sand blasted: $Ra/Rz=0.10$ to 0.17



Honing, Lapped: $Ra/Rz=0.05$ to 0.12



Pulse (Duty ratio 5%): $Ra/Rz=0.095$



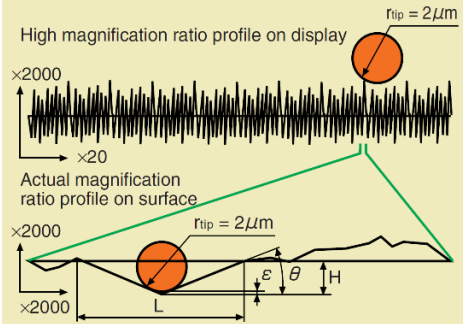
Display aspect ratio & Stylus fall depth in valley

Roughness profile usually displayed as much magnified height deviations than wavelength.

Displayed valley looks sharp but actually wide. Stylus can contact to bottom of valley.

Depth error ε with stylus unable to contact on triangle valley is; $\varepsilon = r_{tip} (1/\cos\theta - 1)$

$\theta < 15^\circ$, or $H/L=0.1-0.01$ on machined surface.



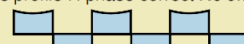
Profile distortion with cutoff

Roughness profile will have bigger profile distortion & smaller amplitude when cutoff λ_c is short.

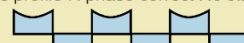
Primary profile P



Roughness profile R phase correct $\lambda_c 0.8$ mm



Roughness profile R phase correct $\lambda_c 0.25$ mm

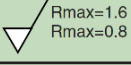
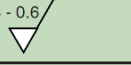
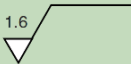
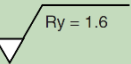
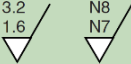


Roughness profile with 2RC filter $\lambda_c 0.25$ mm have big distortion according to phase shift.



ACCURETECH TOKYO SEIMITSU

Comparison of national standards of surface texture measurement

ID. of national standard country		JIS B0601-'82 JIS B0031-'82	ANSI B46.1-'85	NF E05-015('84) NF E05-016('78) NF E05-017('72)	ISO468-'82 ISO4287/1-'84 ISO4288-'85 ISO1302-'78
Specification		former Japan	former U.S.A.	former France	former ISO
Primary profile P	Profile format	Analog signal without filtering	Analog signal with low pass filtering	Analog signal without filtering	Analog signal without filtering
	Evaluation length	1 sampling length 0.25, 0.8, 2.5, 8, & 25	—	not defined	—
P profile parameter	Maximum height	Rmax (S indication)	—	Pt	—
	Ten point height	Rz (Z indication)	—	—	—
	Other P parameters	—	—	Pp, Pa, (Tp)c,	—
	Motif parameters	—	—	R, AR, Kr, W, W'max, W't, AW, Kw	—
	Indication of maximum height < 1.5μm		—		—
Roughness profile R	Unit of height	μm	μm or μin.	μm	μm
	Unit of length	mm	mm or in.	mm	mm
	Filter	2RC	2RC	2RC	2RC
	Long cutoff	λc	λB	λc	λc
	Short cutoff	—	cutoff value 2.5μm	—	—
	Sampling length	L=3 × λc or over	L:1.3-5mm @ λB 0.25 L:2.4-8mm @ λB 0.8 L:5-15mm @ λB 2.5	ℓ	ℓ
	Evaluation length	TL=L=3 × λc or over	—	L = n × ℓ	ℓ n = n × ℓ
R profile Height parameter	Maximum height	—	Peak-to-Valley Height (Rmax, Ry)	Ry	Ry
	Maximum peak to valley height	—	—	Rmax	Rymax
	Ten point height	—	(Rz)	Rz	Rz
	Average peak to valley height	—	—	—	Ry5
	Other peak height parameters	—	(Rp)	Rp	Rp, Rpmax, Rp5, Rm, Rc
ℓ r & λc for peak height parameter	0.25mm	Rmax, Rz ≤ 0.8μm	—	not defined	0.1 < Rz, Ry ≤ 0.5μm
	0.8mm	0.8 < Rmax, Rz ≤ 6.3μm	—	not defined	0.5 < Rz, Ry ≤ 10μm
	2.5mm	6.3 < Rmax, Rz ≤ 25μm	—	not defined	10 < Rz, Ry ≤ 50μm
Indication of Maximum height in case of Rz < 1.5μm		—	—		
R profile averaging parameter	Arithmetic average	Ra (a indication)	Ra	Ra	Ra
	root mean square	—	(Rq)	Rq	Rq
	Skewness, kurtosis	—	(Skewness, Kurtosis)	Sk, Ek	Sk
ℓ r & λc for Ra on non-periodic profile	0.25mm	optional	0.0063 < Sm ≤ 0.05μm	not defined	0.02 < Ra ≤ 0.1μm
	0.8mm	Ra ≤ 12.5μm	0.02 < Sm ≤ 0.16μm	not defined	0.1 < Ra ≤ 2μm
	2.5mm	12.5 < Ra ≤ 100μm	0.063 < Sm ≤ 0.5μm	not defined	2 < Ra ≤ 10μm
Indication of Ra in case of 1.5 < Ra < 3.1μm					
R profile other parameter	Mean spacing	—	Roughness spacing	Sm	Sm
	RMS slope	—	—	Δq	Δq
	material ratio	—	(tp)	—	tp
	Other parameters	—	(Peak count Pc)	S, Δa, λa, λq	S, Δa, λa, λq, Lo, D
Comparison rule of measured value with tolerance limits	Average	average value of all sampling lengths	average value of all sampling lengths	not defined	—
	16% rule	—	—	not defined	16% rule default
	Maximum rule	—	—	not defined	Max rule for parameter with suffix "max"

BS1134 part 1-'88 BS1134 part 2-'90	DIN4768-'90 DIN4771-'77 DIN4775-'82 DIN4776-'90 DIN4777-'90 former Germany	JIS B0601-'94 JIS B0031-'94 former Japan	ASME B46.1-'95 U.S.A.	ISO4287-'97 (JIS B0601-'01) ISO4288-'96 (JIS B0633-'01) ISO12085-'96 (JIS B0631-'00) ISO13565's, (JIS B0671's) ISO1302-'02 EU, U.K. & Japan
Analog signal without filtering	Digital data without filtering	Digital data without filtering	Digital data with λ s filter	Digital data with λ s filter
—	0.5, 1, 5, 15 & 50mm	—	—	= 1 sampling length = Length of the measured feature
—	Pt	—	—	Pt, Pz(=Pt)
—	—	—	—	—
—	—	—	—	Pp, Pv, Pc, Pa, Pq, Psk, Pku, PSm, PΔq, Pmr(c), Pδc, Pmr, Ppq, Pvq, Pmq
—	—	—	—	R, AR, Rx, W, AW, Wx, Wte
—	 15 / Pt 1,6	—	—	 U 0.008- /Pt 1.5
μm (μin)	μm	μm	μm (or μin .)	μm
mm (inch)	mm	mm	mm (or in.)	mm
2RC	Phase correct	Phase correct	Phase correct (or 2RC)	Phase correct
λB	λc	λc	λc	λc
—	—	—	λs	λs
ℓr	ℓc	ℓr	Cutoff length : ℓ	ℓr
$\ell\text{e} = 5 \times \ell\text{r}$	$5 \times \ell\text{c}$	$\ell\text{e} = 5 \times \ell\text{r}$	$L = 5 \times \ell$	$\ell\text{e} = 5 \times \ell\text{r}$ Calculate for each sampling length ℓr
—	Rt	Maximum height Ry in 1 ℓr	Rt	Maximum height Rz in 1 ℓr or total height Rt in 1 ℓe
Ry	Maximum two point height Rmax	—	Rmax	Rz max
Rz	—	Ten point height Rz	—	—
—	Ten point height Rz	Maximum height Ry	Rz	Average method Rz
—	—	—	Rp, Rpm, Rv	Rp, Rv, Rc
$0.1 < \text{Rz} \leq 0.5\mu\text{m}$	$0.1 < \text{Rz} \leq 0.5\mu\text{m}$	$0.1 < \text{Rz}, \text{Ry} \leq 0.5\mu\text{m}$	$0.02 < \text{Ra} \leq 0.1\mu\text{m}$	$0.1 < \text{Rz} \leq 0.5\mu\text{m}$
$0.5 < \text{Rz} \leq 10\mu\text{m}$	$0.5 < \text{Rz} \leq 10\mu\text{m}$	$0.5 < \text{Rz}, \text{Ry} \leq 10\mu\text{m}$	$0.1 < \text{Ra} \leq 2\mu\text{m}$	$0.5 < \text{Rz} \leq 10\mu\text{m}$
$10 < \text{Rz} \leq 50\mu\text{m}$	$10 < \text{Rz} \leq 50\mu\text{m}$	$10 < \text{Rz}, \text{Ry} \leq 50\mu\text{m}$	$2 < \text{Ra} \leq 10\mu\text{m}$	$10 < \text{Rz} \leq 50\mu\text{m}$
 Ry = 1.6	 Rmax = 1,6	 Ry1.6-0.8 λc 0.25	 Rmax = 1.6	 U 0.008-2.5/Rz 1.5 L -0.25/Rz 0.7
Ra	Ra	Ra	Ra	Ra
—	—	—	Rq	Rq
—	—	—	Rsk, Rku	Rsk, Rku
$0.02 < \text{Ra} \leq 0.1\mu\text{m}$	$0.02 < \text{Ra} \leq 0.1\mu\text{m}$	$0.02 < \text{Ra} \leq 0.1\mu\text{m}$	$0.02 < \text{Ra} \leq 0.1\mu\text{m}$	$0.02 < \text{Ra} \leq 0.1\mu\text{m}$
$0.1 < \text{Ra} \leq 2\mu\text{m}$	$0.1 < \text{Ra} \leq 2\mu\text{m}$	$0.1 < \text{Ra} \leq 2\mu\text{m}$	$0.1 < \text{Ra} \leq 2\mu\text{m}$	$0.1 < \text{Ra} \leq 2\mu\text{m}$
$2 < \text{Ra} \leq 10\mu\text{m}$	$2 < \text{Ra} \leq 10\mu\text{m}$	$2 < \text{Ra} \leq 10\mu\text{m}$	$2 < \text{Ra} \leq 10\mu\text{m}$	$2 < \text{Ra} \leq 10\mu\text{m}$
 3.2 / 1.6  N8 / N7	 3.2 / 1.6	 1.6-3.2	 3.2 / 1.6	 U*2RC" -0.8/Ra75 3.1 L*2RC" -0.8/Ra75 1.5
Sm	—	Sm	Sm	RSm
—	—	—	Δq	RΔq
tp	—	tp	tp	Rmr(c)
S	—	S	Htp, Δa, SAE Peak PPI, Peak density Pc	Rδc, Rmr, Rpk, Rvk, Rk, Mr1, Mr2, Rpq, Rvq, Rmq
—	—	average value of all sampling lengths	not defined	average value of all sampling lengths
16% rule	16% rule for Ra, Rz	—	not defined	16% rule default
Max rule for parameter with suffix "max"	Max rule for Rmax	—	not defined	Max rule for parameter with suffix "max"